

BS ISO 16413:2013



BSI Standards Publication

**Evaluation of thickness, density
and interface width of thin
films by X-ray reflectometry
— Instrumental requirements,
alignment and positioning,
data collection, data analysis
and reporting**

National foreword

This British Standard is the UK implementation of ISO 16413:2013.

The UK participation in its preparation was entrusted to Technical Committee CII/60, Surface chemical analysis.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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Amendments issued since publication

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